



US00D334147S

# United States Patent [19]

[11] Patent Number: **Des. 334,147**

**Aukstikalnis et al.**

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- [54] **ELECTRICAL TEST PROBE**
- [75] Inventors: **Glen Aukstikalnis, Vancouver; Mark Nightingale, Camas, both of Wash.**
- [73] Assignee: **Tektronix, Inc., Wilsonville, Oreg.**
- [\*\*] Term: **14 Years**
- [21] Appl. No.: **538,941**
- [22] Filed: **Jun. 13, 1990**
- [52] U.S. Cl. .... **D10/80**
- [58] Field of Search ..... **D10/80, 103, 46; 29/844, 847, 862; 174/89, 750; 324/72.5, 156, 149, 158 P; 439/482, 585, 374, 824, 819**

Passive Probes; Subminiature Passive Probes; etc.: ©1989; pp. 4, 6, 8, 10, 12, 14, 18-20, 24. Tegam Inc., Thermocouple Probes, Aug. 1987; cover page.

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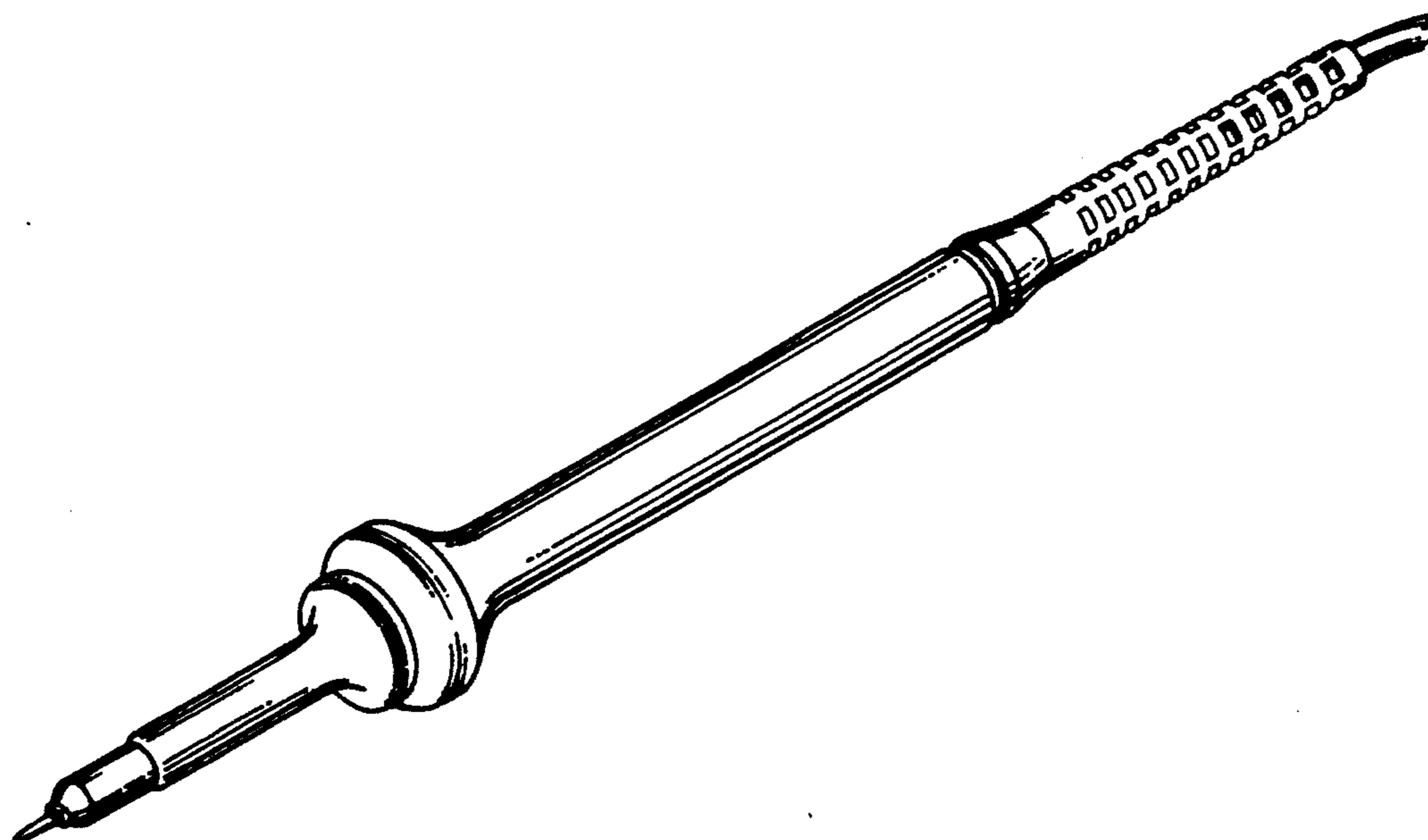
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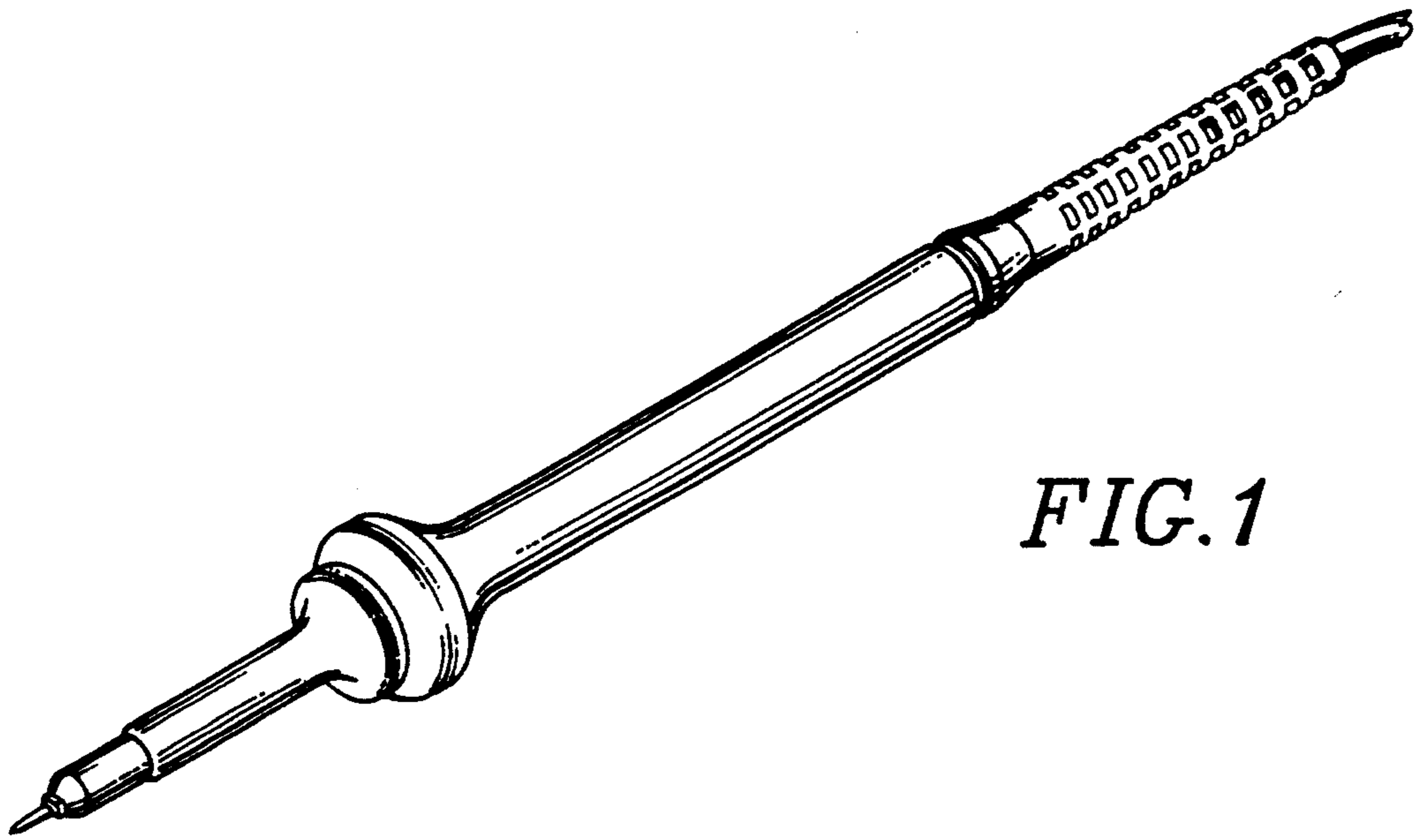
[57] **CLAIM**  
The ornamental design for an electrical test probe, as shown.

**OTHER PUBLICATIONS**  
Tektronix, Inc., Tek Accessories; Minature Modular

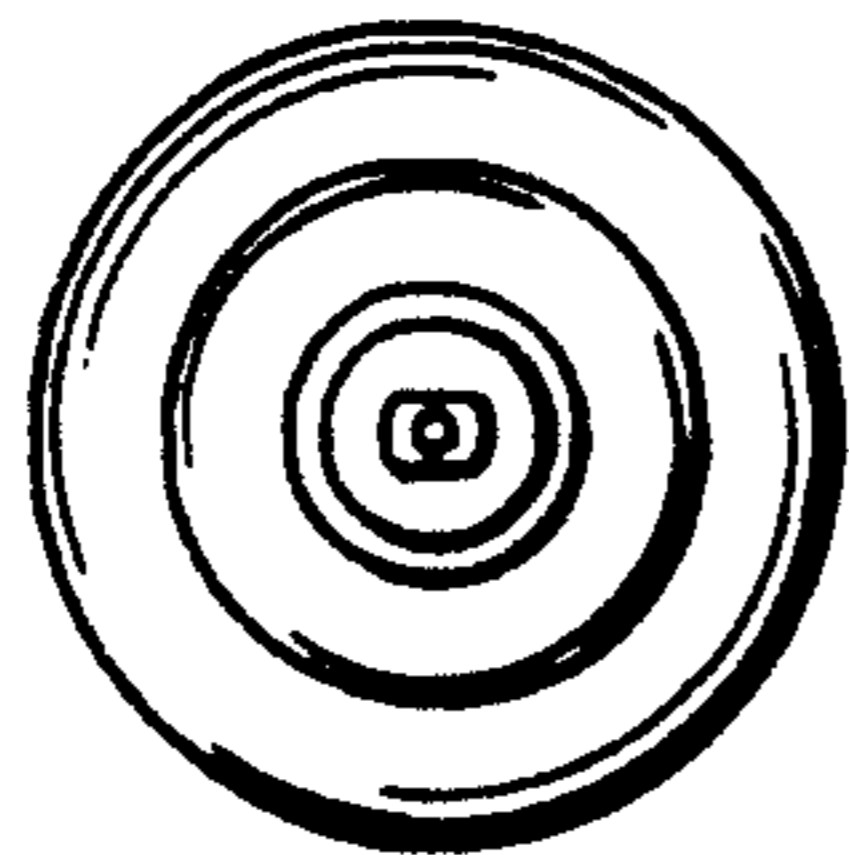
### DESCRIPTION

FIG. 1 is a perspective view of an electrical test probe showing our new design;  
FIG. 2 is a left side elevational view thereof, the right side elevational view being a mirror image;  
FIG. 3 is a top plan view thereof;  
FIG. 4 is a bottom plan view thereof;  
FIG. 5 is a front elevational view thereof; and,  
FIG. 6 is a rear elevational view thereof.

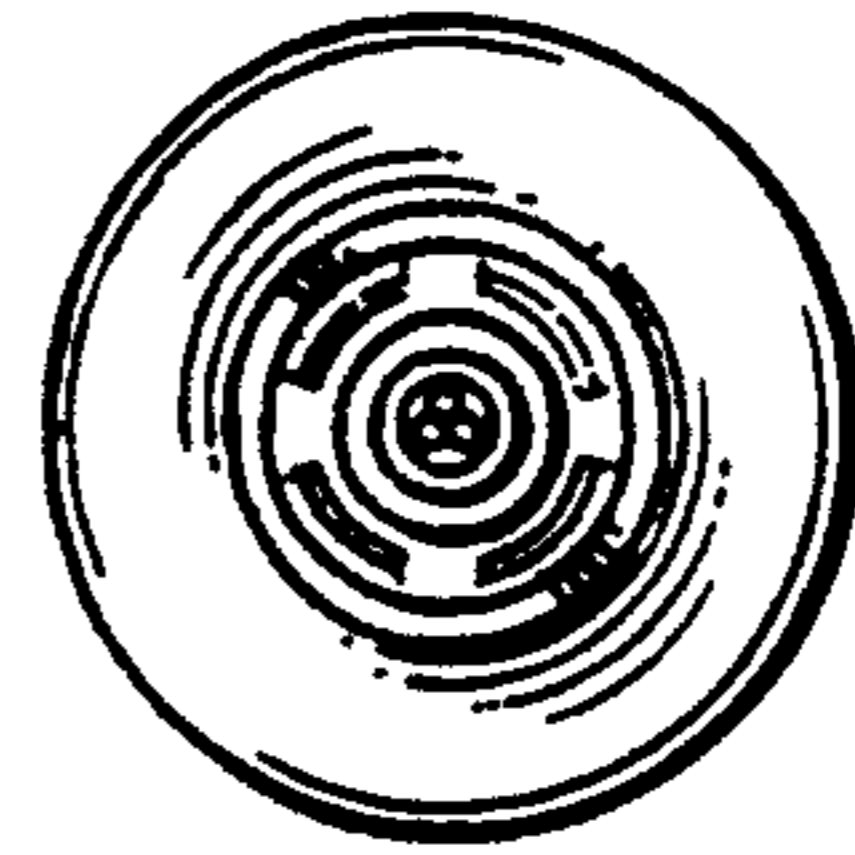




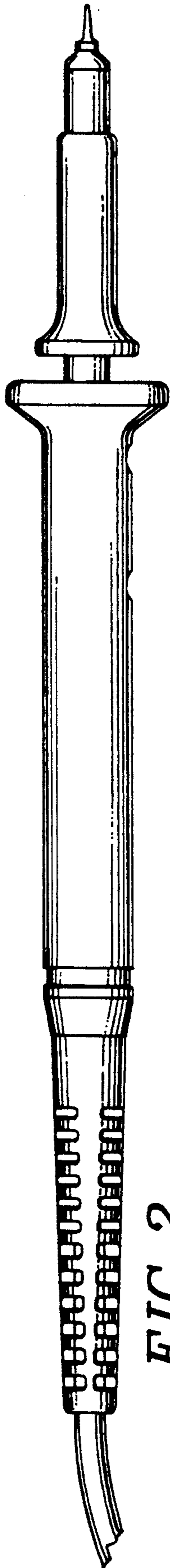
*FIG. 1*



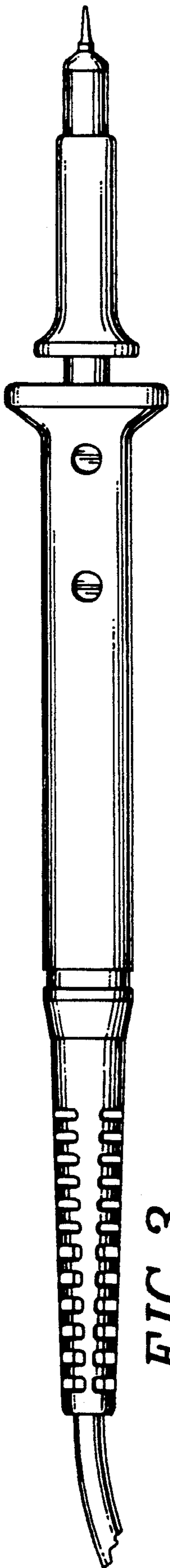
*FIG. 6*



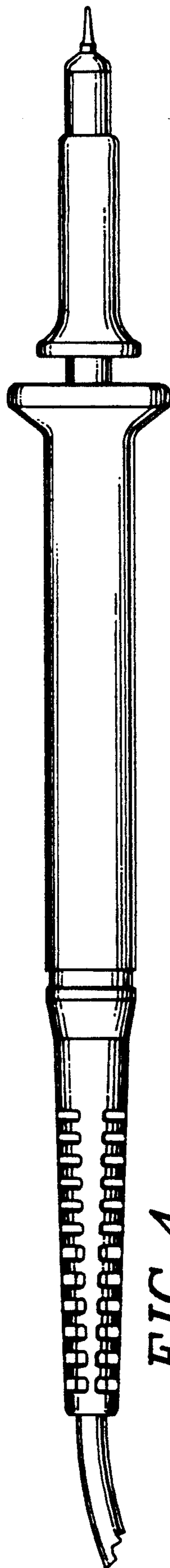
*FIG. 5*



*FIG. 2*



*FIG. 3*



*FIG. 4*